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SFENG 1984 ()

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SF-18.0x76.0

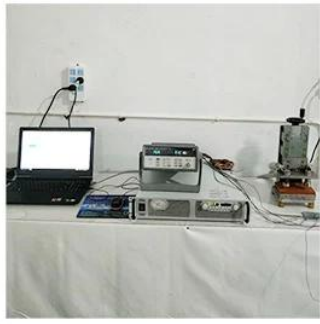
Technical drawing showing a side view and an end view of a probe assembly. The side view includes dimensions for diameters (φ1.0, φ16.0, φ11.0, φ12.0, φ33, φ3.3, φ18.0, φ2.0), lengths (12.0, 16.0, 31.0, 8.0, 76.0, 7.5, 4.0, 3.0), and thread specifications (M12.0x1.0, S16). A detail of a spring is shown with dimensions 0.1, 75°, 0.6, and 0.35. The end view shows diameters φ33, φ3.3, φ16.0, φ18.0, φ2.0 and lengths 27.0, 16.0, 18.0, 2.4.

Materials (Plated) (材質與鍍層):
 Barrel (針套) : POM (賽鋼) /
 Plunger (電壓針軸) : BeCu (鈹銅) , Au on Ni Plated
 Plunger (電流針軸) : Cu (探針專用銅) , Au on Ni Plated
 Spring (彈弓) : Spring Wire (彈簧鋼線) , Ni Plate
 Insulator (絕緣體) : PEEK or PTFE /

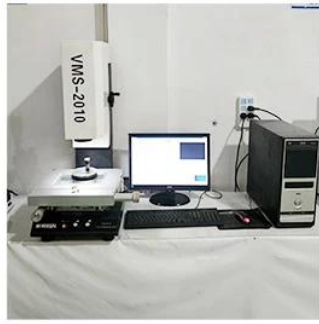
Specifications (技術要求):
 Current Rating (額定電流) : ??A
 Contact Resistance (接觸電阻) : ??mΩ

	名稱	移動距離 (mm)	1/2 壓縮	全壓縮
彈力規格	電流針	12	11kgf	15.5kgf
	電壓針	3	-	1200gf

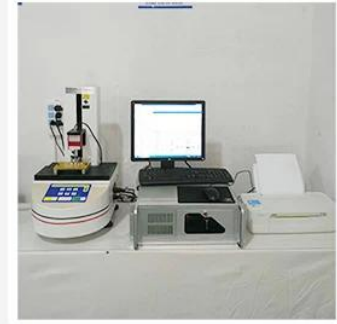
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1. Agilent current testing



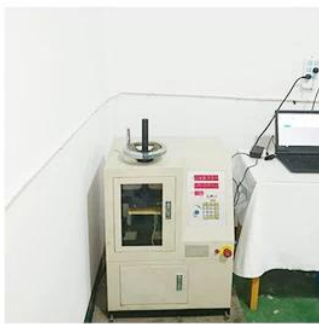
2. Quadratic element



3. Load Curve Meter



4. Bond Test



5. Life Fatigue Test



6. Microscope











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